Notice of References Cited

Application/Control No.

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Examiner

James M Hannett

Applicant(s)/Patent Under
Reexamination
SAKURAI ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,512,546 /	01-2003	Decker et al.	348/308
	В	US-5,990,471 /	11-1999	Watanabe, Takashi	250/208.1
	С	US-5,818,052	10-1998	Elabd, Hammam	250/370.09
	D	US-2002/0154231 <	10-2002	Decker et al.	348/302
	E	US-6,538,693 /	03-2003	Kozuka, Hiraku	348/241
	F	US-2001/0007471 /	07-2001	Beiley, Mark A.	348/241
	G	US-6,587,146 /	07-2003	Guidash, Robert M.	348/308
	Н	US-6,317,154 /	11-2001	Beiley, Mark A.	348/308
	ı	US-6,243,134	06-2001	Beiley, Mark A.	348/308
	J	US-6,133,862 /	10-2000	Dhuse et al.	341/118
	к	US-6,011,251	01-2000	Dierickx et al.	250/208.1
	L	US-5,172,249	12-1992	Hashimoto, Seiji	358/482
_	М	US-			//

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
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NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)							
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.